S	earc	h Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/525,714	SEGAWA ET AL.	
Examiner	Art Unit	
	1400	

SEARCHED					
Class	Subclass	Date	Examiner		
•					
			<del>-</del>		
****					
•••					
	·.				
	ľ				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	·	,		
-				
	J			

(INCLUDING SEARCH	ES STRATEGY	)
	DATE	EXMR
EAST-see attached notes	8/21/2007	RTC
		. (